

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Group Art Unit: 2858
Prior Examiner: J. Hollington

*4 P.R. Hmde. R
G.H. Hmde. R
10/16/01*

In Re NEW PATENT APPLICATION Of:

Applicant: Mikio OHTAKI)
Appln. No.: To Be Assigned)
Divisional Appl. of 09/434,490)
Filed: July 16, 2001)
For: SEMICONDUCTOR DEVICE)
TEST APPARATUS)
Atty Ref.: KAN 120D1)

**PRELIMINARY
AMENDMENT**

July 16, 2001

Commissioner for Patents
Washington, D.C. 20231

Sir:

Preliminary to examination, please amend the application as follows:

IN THE TITLE

Please change the title to --SEMICONDUCTOR DEVICE TEST METHOD--

IN THE SPECIFICATION

Page 1, before line 1, insert --This is a Divisional of Applicant's
copending Application Serial No. 09/434,490.--

*8-0000-8
D: 7/10, -*